

Search Notes

Application/Control No.

10/004,885

Examiner

Khai M. Nguyen

Applicant(s)/Patent under
Reexamination

ABURAKAWA ET AL.

Art Unit

2687

SEARCHED

Class	Subclass	Date	Examiner
455	561 550.1 560 73	9/9/2005	KN
379	56.2 56.1	9/9/2005	KN
379	429	9/9/2005	KN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
see	attached		KN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (see attached)		kn